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APPLICATION NO.	CATION NO. FILING DATE FIRST NAMED INVE		ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/717,406 11/19/2003		Charles Q. Zhan	120 06741US	7240	
128	7590 05/05/2005		EXAMINER		
HONEYWELL INTERNATIONAL INC.			LE, TOAN M		
P O BOX 224		ART UNIT	PAPER NUMBER		
MORRISTOWN, NJ 07962-2245			2863		
			DATE MAILED: 05/05/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application	n No	Applicant(s)				
		10/717,40		ZHAN ET AL.				
Office Action Summary		Examiner		Art Unit				
		Toan M. Le	<b>a</b>	2863				
	The MAILING DATE of this communication a	1						
Period fo		.,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		••••••				
THE - Exté after - If the - If NC - Failt Any	ORTENED STATUTORY PERIOD FOR REF MAILING DATE OF THIS COMMUNICATION nsions of time may be available under the provisions of 37 CFR SIX (6) MONTHS from the mailing date of this communication. e period for reply specified above is less than thirty (30) days, a red period for reply is specified above, the maximum statutory perior to reply within the set or extended period for reply will, by state reply received by the Office later than three months after the maked patent term adjustment. See 37 CFR 1.704(b).	N. 1.136(a). In no eve reply within the statu od will apply and wil lute, cause the appl	nt, however, may a reply be tim tory minimum of thirty (30) day I expire SIX (6) MONTHS from cation to become ABANDONE	nely filed s will be considered timely. the mailing date of this communicat D (35 U.S.C. § 133).	ion.			
Status								
1)[\]	Responsive to communication(s) filed on 14	February 200	05	•				
2a)□								
3)□								
٠,۵	closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
Disposit	ion of Claims	·						
-		on						
4)(2)	Claim(s) <u>1-22</u> is/are pending in the application.  4a) Of the above claim(s) is/are withdrawn from consideration.							
5)⊠	5)⊠ Claim(s) <u>21 and 22</u> is/are allowed.							
6)⊠								
7)⊠								
8)	8) Claim(s) are subject to restriction and/or election requirement.							
Applicat	ion Papers							
9)[]	The specification is objected to by the Exam	iner.						
,	10)⊠ The drawing(s) filed on <u>19 November 2003</u> is/are: a)⊠ accepted or b)□ objected to by the Examiner.							
,,	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
	Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).							
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.								
Priority	under 35 U.S.C. § 119							
12)	Acknowledgment is made of a claim for fore	ign priority und	der 35 U.S.C. § 119(a	)-(d) or (f).				
-	□ All b)□ Some * c)□ None of:				`			
ĺ	1. Certified copies of the priority documents have been received.							
	2. Certified copies of the priority docume	ents have bee	n received in Applicat	ion No				
	3. Copies of the certified copies of the p	riority docume	ents have been receive	ed in this National Stage				
	application from the International Bur	•						
* ;	See the attached detailed Office action for a	list of the certi	fied copies not receive	∍d.				
Attachme			4) T 1=4==================================	(DTO 442)				
	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-948)		4) Interview Summary Paper No(s)/Mail D	ate				
3) 🛛 Info	rmation Disclosure Statement(s) (PTO-1449 or PTO/SB/ er No(s)/Mail Date <u>2/14/05</u> .	(08)		Patent Application (PTO-152)				

#### **DETAILED ACTION**

## Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

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(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claims 1-2, 4-5, 7-9, 11, 14-16, and 18 are rejected under 35 U.S.C. 102(a) as being anticipated by "Applying MultiResolution Analysis for Processing of Hydraulic Pump Fault Signal", Wanlu et al. (referred hereafter Wanlu et al.).

Referring to claims 1, 8, and 15, Wanlu et al. disclose a method; apparatus; a computer program embodied on a computer readable medium and operable to be executed by a processor, the computer program comprising computer readable program code (Abstract); comprising:

decomposing a signal comprising a plurality of process variable measurements into a plurality of resolution levels, the process variable measurements associated with operation of a valve (page 2, 2<sup>nd</sup> col., lines 19-37; equations 11-17; figure 1);

grouping the resolution levels into a plurality of groups (page 2, 2<sup>nd</sup> col., lines 19-37: equations 11-17); and

identifying one or more defect indicators for at least some of the resolution levels using the groups, the one or more defect indicators associated with a possible defect in the valve (page 4. 1st col., 2nd paragraph and last paragraph to page 4, 2nd col., 1st and last paragraphs; figure 2).

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As to claims 2, 9, and 16, Wanlu et al. disclose a method; apparatus; a computer program embodied on a computer readable medium and operable to be executed by a processor, the computer program comprising computer readable program code, wherein:

decomposing the signal comprises performing wavelet decomposition to generate wavelet coefficients at each of the resolution levels (page 2, 2<sup>nd</sup> col., lines 19-37; page 3, 2<sup>nd</sup> col., last paragraph; table 1);

grouping the resolution levels comprises grouping the wavelet coefficients into groups (page 2, 2<sup>nd</sup> col., lines 19-37; equations 11-17); and

identifying the one or more defect indicators comprises performing singularity detection using the groups of wavelet coefficients (page 4, 1<sup>st</sup> col., 2<sup>nd</sup> paragraph and last paragraph to page 4, 2<sup>nd</sup> col., 1<sup>st</sup> and last paragraphs; figure 2).

Referring to claims 4, 11, and 18, Wanlu et al. disclose a method; apparatus; a computer program embodied on a computer readable medium and operable to be executed by a processor, the computer program comprising computer readable program code, wherein the one or more defect indicators identify one or more jumps in the process variable measurements (page 4, 2<sup>nd</sup> col., last paragraph; figure 2).

As to claim 5, Wanlu et al. disclose a method, wherein the one or more jumps represent one or more deterministic signal changes where the process variable measurements change by a threshold amount within a given time period (page 4, 2<sup>nd</sup> col., last paragraph; figure 2).

Referring to claims 7 and 14, Wanlu et al. disclose a method; apparatus; a computer program embodied on a computer readable medium and operable to be executed by a processor, the computer program comprising computer readable program code, wherein grouping the

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resolution levels into the plurality of groups comprises grouping the adjacent three resolution levels into groups, the groups forming overlapping groups where at least some of the resolution levels form part of two or more groups (page 2, 2<sup>nd</sup> col., lines 19-37; equations 11-17; page 4, 2<sup>nd</sup> col., 1<sup>st</sup> paragraph; figure 2).

Claims 3, 6, 10, 12-13, 17, 19-20 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The reason for allowance of the claims 3, 6, 10, 12-13, 17, 19-20 is the inclusion of steps of determining a probability of a valve defect based on the selected resolution level from measurements of a flow rate through the valve and generating a second signal for a valve adjuster.

Wanlu et al. neither teach nor suggest those limitations.

### Allowable Subject Matter

Claims 21-22 are allowed.

The reason for allowance for the claims 21-22 is the inclusion of a controller operable to generate output values for adjusting the valve based on the process variable measurements associated with the operation of the valve.

Wanlu et al. neither teach nor suggest this feature.

#### Remarks:

# Response to Arguments

Applicant's arguments filed 2/14/05 have been fully considered but they are not persuasive.

Referring to claims 1, 8, and 15, Applicant argues that ""Wanlu lacks any mention of grouping decomposition layers into multiple groups and then identifying defect indicators using the multiple groups."

Wanlu discloses "According to the multi-resolution analysis [4], there is a set of recurrence decomposition formulas for the signal f(t) as follows, equations 11-17. Where  $A_j$  f(t) is the low-frequency approximation of  $f(t) \in L^2(R)$  on the scale  $2^j$ .  $D_j$  f(t) is the high-frequency detail of  $f(t) \in L^2(R)$  on the scale  $2^j$ . The coefficient sequence  $\{h_n; n \in Z\}$  is the low-pass filter coefficients corresponding to the scaling function  $\phi(t)$ . The coefficient sequence  $\{g_n; n \in Z\}$  is the high-pass filter coefficients corresponding to the wavelet function  $\psi(t)$ . The two coefficient sequences constitute the orthogonal conjugate filters." on page 2,  $2^{nd}$  col., lines 19-37. And "The characteristic frequency of the shoe-loosing fault is equal to the rotational frequency. When we conduct the threshold noise elimination to d1d2d3, the frequency band of the noise elimination is  $0.625\sim5$ kHz, the ultra-harmonics of the fault characteristic signal loses a little." on page 4,  $1^{st}$  col.,  $2^{nd}$  paragraph.

Thus, Wanlu does disclose grouping decomposition layers into multiple groups in the sum of  $A_j$  f(t) for low frequency approximation and in the sum of  $D_j$  f(t) for high frequency and then identifying defect indicators using the multiple groups.

#### Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Toan M Le whose telephone number is (571) 272-2276. The examiner can normally be reached on Monday through Friday from 9:00 A.M. to 5:30 P.M..

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Barlow can be reached on (571) 272-2269. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Toan Le

April 20, 2005

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